TEXAS INSTRUMENTS 12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20190516001.1
Transfer of select C10 devices from ANAM-1 to DMOS5 Wafer Fab site
Change Notification / Sample Request

Date: May 21, 2019
To: TOKYO ELECTRON DEVICE (DSTR) PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Team (PCN_ww_admin_team@list.ti.com). For sample requests or sample related questions, contact the TI Samples Team at pcn_sr_team@list.ti.com.

PCN Team
SC Business Services

20190516001.1
Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
CDCVF2505D	null
CDCVF2505PW	null
CDCVF25081PW	null
CDCVF2505DR	null
CDCVF2505PWR	null
SN65LV1023ADBR	null
CDCVF2310PWR	null
SN65LV1023ADB	null

Technical details of this Product Change follow on the next page(s).

PCN Number:	20190516001.1	**PCN Date:**	May 21, 2019
Title:	Transfer of select C10 devices from ANAM-1 to DMOS5 Wafer Fab site		
Customer Contact:	PCN Manager	**Dept:**	Quality Services
Proposed 1st Ship Date:	Aug 21, 2019	**Estimated Sample Availability:**	Date provided at sample request.

Change Type:

☐	Assembly Site	☐	Assembly Process	☐	Assembly Materials
☐	Design	☐	Electrical Specification	☐	Mechanical Specification
☐	Test Site	☐	Packing/Shipping/Labeling	☐	Test Process
☐	Wafer Bump Site	☐	Wafer Bump Material	☐	Wafer Bump Process
☒	Wafer Fab Site	☐	Wafer Fab Materials	☐	Wafer Fab Process
		☐	Part number change		

PCN Details

Description of Change:

This change notification is to announce the transfer of select devices from ANAM-1 to the DMOS5 Wafer Fab site. Fab support from ANAM-1 has been discontinued. Buffer inventory has been built to cover the notification period of this change notification.

Current (Discontinued)			New (Transfer to Location)		
Current Fab Site	**Fab Process**	**Wafer Diameter**	**New Fab Site**	**Fab Process**	**Wafer Diameter**
ANAM-1	C10	200mm	DMOS5	C10	200mm

Qual details are provided in the Qual Data Section.

Reason for Change:

Discontinued Fab support from ANAM-1

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
ANAM-1	ANM	KOR	Bucheon-si

New Fab Site

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
DP1DM5	**DM5**	**USA**	**Dallas**

Sample product shipping label (not actual product label)

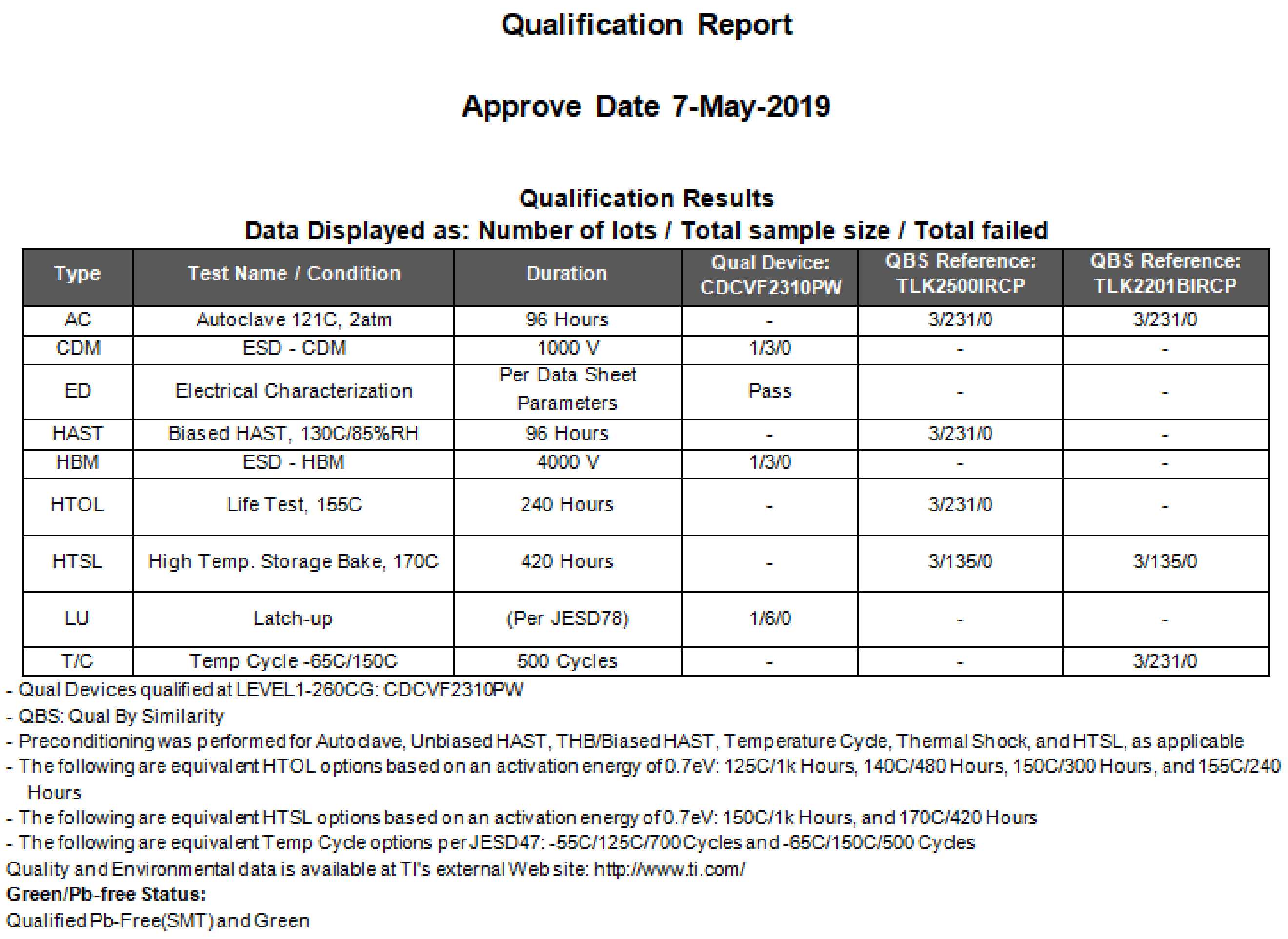
TEXAS INSTRUMENTS
MADE IN: Malaysia
2DC: 2Q:
MSL 2 /260C/1 YEAR SEAL DT
MSL 1 /235C/UNLIM 03/29/04
OPT:
ITEM: 39
LBL: 5A (L)TO:1750

(1P) SN74LS07NSR
(Q) 2000 (D) 0336
(31T)LOT: 3959047MLA
(4W) TKY(1T) 7523483SI2
(P)
(2P) REV: (V) 0033317
(20L) CSO: SHE (21L) CCO:USA
(22L) ASO: MLA (23L) ACO: MYS

Product Affected Group:

CDCVF2310PW	CDCVF2505DG4	CDCVF2505PWRG4	HPA00771PWR
CDCVF2310PWG4	CDCVF2505DR	CDCVF25081PW	SN65LV1023ADB

CDCVF2310PWR	CDCVF2505DRG4	CDCVF25081PWG4	SN65LV1023ADBR
CDCVF2310PWRG4	CDCVF2505PW	CDCVF25081PWR	SN65LV1023ARHBR
CDCVF2505D	CDCVF2505PWR	CDCVF25081PWRG4	SN65LV1023ARHBT



Qualification Report

Approve Date 7-May-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: CDCVF2310PW	QBS Reference: TLK2500IRCP	QBS Reference: TLK2201BIRCP
AC	Autoclave 121C, 2atm	96 Hours	-	3/231/0	3/231/0
CDM	ESD - CDM	1000 V	1/3/0	-	-
ED	Electrical Characterization	Per Data Sheet Parameters	Pass	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-
HBM	ESD - HBM	4000 V	1/3/0	-	-
HTOL	Life Test, 155C	240 Hours	-	3/231/0	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	3/135/0	3/135/0
LU	Latch-up	(Per JESD78)	1/6/0	-	-
T/C	Temp Cycle -65C/150C	500 Cycles	-	-	3/231/0

- Qual Devices qualified at LEVEL1-260CG: CDCVF2310PW
- QBS: Qual By Similarity
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Qualification Report

Approve Date 7-May-2019

Qualification Results
Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: SN65LV1023ADB	QBS Reference: TLK2500IRCP	QBS Reference: TLK2201BIRCP
AC	Autoclave 121C, 2atm	96 Hours	-	3/231/0	3/231/0
CDM	ESD - CDM	1000 V	1/3/0	-	-
ED	Electrical Characterization	Per Data Sheet Parameters	Pass	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-
HBM	ESD - HBM	3000 V	1/3/0	-	-
HTOL	Life Test, 155C	240 Hours	-	3/231/0	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	3/135/0	3/135/0
LU	Latch-up	(Per JESD78)	1/6/0	-	-
T/C	Temp Cycle -65C/150C	500 Cycles	-	-	3/231/0

- Qual Devices qualified at LEVEL1-260CG: SN65LV1023ADB
- QBS: Qual By Similarity
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	**E-Mail**
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN_ww_admin_team@list.ti.com